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Altiparmak, F.; Dengiz, B.; Smith, A.E.  
Reliability, IEEE Transactions on  
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Digital Object Identifier 10.1109/TR.2008.2011854  
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- 2. System Reliability Evaluation for a Multistate Supply Chain Network With Failure Nodes Using Minimal Paths**  
Yi-Kuei Lin  
Reliability, IEEE Transactions on  
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- 3. Incorporating Common-Cause Failures Into the Modular Hierarchical Systems Analysis**  
Liudong Xing; Shrestha, A.; Meshkat, L.; Wendai Wang  
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Volume 58, Issue 1, Date: March 2009, Pages: 10-19  
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Lollini, P.; Bondavalli, A.; di Giandomenico, F.  
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- 6. Simultaneous Quality and Reliability Optimization for Microengines Subject to Degradation**  
Hao Peng; Qianmei Feng; Coit, D.W.  
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Volume 58, Issue 1, Date: March 2009, Pages: 98-105  
Digital Object Identifier 10.1109/TR.2008.2011672  
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**7. Residual Life Predictions in the Absence of Prior Degradation Knowledge**

Gebraeel, N.; Elwany, A.; Jing Pan

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